







Development of full-field deflectometry for characterization of free-form mirrors for space applications

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2 fullfield deflectometers for 2 types of mirrors

Freeform mirrors

- In situ measurement
- Characterization of small mirrors or subaperture stighting
 - FOV: Ø=30mm
 - Angular acceptance: ±2°
- · Fullfield deflectometry
 - Phase-shifting Schlieren
 - Measurement of the slope maps along 2 perpendicular directions
- Instrument
 - Fringe projection system with fast SLM at the focal plane of the projection lens
 - Telecentric imaging system
- Output
 - Absolute reconstruction of the shape of the mirror
 - Characterization of residual waviness
- Easy to use
 - Very simple alignment
 - No calibration
- Cost effective

Large concave mirrors

- Characterization of large concave mirrors
 - FOV>30°
 - Working distance: validated from 300mm to1000mm
- Fullfield deflectometry
 - Measurement of the deformation of a fringe pattern
- Instrument
 - 5" fringe display with custom backlight
 - Imaging system
 - Illumination & imaging systems are calibrated
 - Phase-shifting method
- Absolute reconstruction of the shape of the mirror
 - Iterative algorithm
- Easy to use
 - Very simple alignment
 - No calibration
- Cost effective



